



EMI TEST REPORT

Test Report No. : 10946205H-B

Applicant : Sharp Corporation, Communication Systems Division
Type of Equipment : Cellular Phone
Model No. : 501SH
FCC ID : APYHRO00227
Test standard : FCC Part 15 Subpart B 2015 Class B
Test Result : Complied

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
6. This test report covers EMC technical requirements. It does not cover administrative issues such as Manual or non-EMC test related Requirements. (if applicable)

Date of test: September 10 and 11, 2015

**Representative
test engineer:**

K. Yamamoto

Koji Yamamoto
Engineer
Consumer Technology Division

Approved by :

T. Hatahara

Takahiro Hatahara
Leader
Consumer Technology Division



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.
*As for the range of Accreditation in NVLAP, you may refer to the WEB address,
<http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap>

UL Japan, Inc.

Ise EMC Lab.

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13-EM-F0429

REVISION HISTORY

Original Test Report No.: 10946205H-B

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CONTENTS	PAGE
SECTION 1: Customer information	4
SECTION 2: Equipment under test (E.U.T.)	4
SECTION 3: Test specification, procedures & results	5
SECTION 4: Operation of E.U.T. during testing	7
SECTION 5: Conducted Emission	8
SECTION 6: Radiated Emission	9
APPENDIX 1: Data of EMI test	10
Conducted Emission	10
Radiated Emission	12
APPENDIX 2: Test instruments	16
APPENDIX 3: Photographs of test setup.....	17
Conducted Emission	17
Radiated Emission	18
Worst Case Position (Horizontal: X-axis/ Vertical:X-axis)	20

SECTION 1: Customer information

Company Name : Sharp Corporation, Communication Systems Division
Address : 2-13-1 Iida Hachihonmatsu HigashiHiroshima-City, Hiroshima, 739-0192
Japan
Telephone Number : +81-82-420-1552
Facsimile Number : +81-82-420-1555
Contact Person : Hachiro Hidaka

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Cellular Phone
Model No. : 501SH
Serial No. : Refer to Section 4, Clause 4.2
Receipt Date of Sample : September 10, 2015
Country of Mass-production : China
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product description

Feature of EUT : 501SH is Dual-band WCDMA(FDD I / VIII) & Tri-band GSM(900 / 1800 / 1900) Dual-mode Cellular Phone.
The EUT has the function that Bluetooth technology interface for establishing contact and transmitting data with certain device.
Clock frequencies in the system : CPU: 1.0944 GHz (max)
Source oscillation: 19.2 MHz, 27 MHz(DTV),
RTC: 32.768 kHz

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SECTION 3: Test specification, procedures & results

3.1 Test specification

Test specification: Test specification: FCC Part 15 Subpart B: 2015, final revised on September 8, 2015

Title : FCC 47CFR Part15 Radio Frequency Device
Subpart B Unintentional Radiators

3.2 Procedures and results

Item	Test Procedure	Limits	Deviation	Worst margin	Result
Conducted emission	ANSI C63.4: 2009 7. AC powerline conducted emission measurements	Class B	N/A	[QP] 2.6 dB 0.16862 MHz, L [AV] 4.4 dB 0.16862 MHz, L	Complied
Radiated emission	ANSI C63.4: 2009 8. Radiated emission measurements	Class B	N/A	7.5 dB 797.920 MHz, Horizontal, QP	Complied

*Note: UL Japan, Inc's EMI Work Procedure 13-EM-W0420.

3.3 Addition to standard

No addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi- anechoic chamber)	Conducted emission (+dB)
	150 kHz - 30 MHz
No.1	3.5 dB
No.2	3.5 dB
No.3	3.4 dB
No.4	3.5 dB

Test room (semi- anechoic chamber)	Radiated emission						
	(3 m*)(+dB)				(1 m*)(+dB)		(0.5 m*)(+dB)
	9 kHz - 30 MHz	30 MHz - 300 MHz	300 MHz - 1 GHz	1 GHz - 10 GHz	10 GHz - 18 GHz	18 GHz - 26.5 GHz	26.5 GHz - 40 GHz
No.1	4.3 dB	5.1 dB	6.2 dB	5.5 dB	5.8 dB	5.8 dB	4.3 dB
No.2	4.2 dB	5.1 dB	6.2 dB	5.4 dB	5.7 dB	5.9 dB	5.6 dB
No.3	4.4 dB	5.1 dB	6.3 dB	5.2 dB	5.5 dB	5.8 dB	5.5 dB
No.4	4.7 dB	5.3 dB	6.3 dB	5.3 dB	5.7 dB	5.9 dB	5.5 dB

*3m/1m/0.5m = Measurement distance

Conducted emission test

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

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3.5 Test Location

UL Japan, Inc. Ise EMC Lab. *NVLAP Lab. code: 200572-0
4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN
Telephone : +81 596 24 8999 Facsimile : +81 596 24 8124

	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	4.0 x 4.5 x 2.7m	4.0 x 4.5 m	-
No.6 measurement room	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	8.8 x 4.6 x 2.8m	2.4 x 2.4m	-
No.11 measurement room	-	6.2 x 4.7 x 3.0m	4.8 x 4.6m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test data, Test instruments, and Test set up

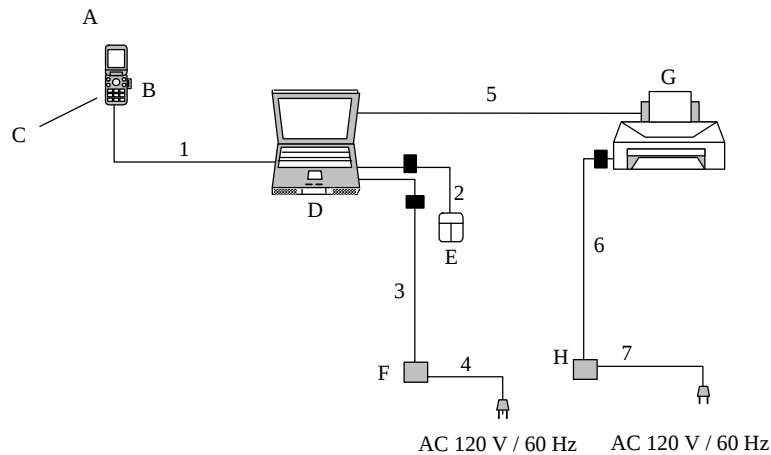
Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating modes

The mode(s) : 1) USB Data Com Mode
The USB data is communicated between EUT and Personal computer (Pair of EUT).
2) Standby Mode
Standby state for USB communication.

4.2 Configuration and peripherals



■ : Ferrite core which has been standard on support equipment.

*Cabling and setup were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Cellular Phone	501SH	004401/11/556864/0	Sharp Corporation	EUT
B	microSD Memory Card	SD-C02G	None	TOSHIBA	-
C	Lithium-Ion Battery	SHBFN1	YGU1A	Sharp Corporation	EUT
D	Personal Computer	PP11L	CN-0D4571-48643-58P-1053	Dell	-
E	Mouse	M-UAG120	LZ733B70EVV	TOSHIBA	-
F	AC Adapter(PC)	LA65NS1-00	CN-0YD637-71615-64Q-2243	Dell	-
G	Printer	895Cxi	SG8BA1W18J	Hewlett Packard	-
H	AC Adapter(Printer)	C4557-60004	C8L01B	Hewlett Packard	-

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	USB Data Cable	0.95	Shielded	Shielded	-
2	Mouse Cable	0.72	Unshielded	Unshielded	-
3	AC Adaptor Cable (PC)	1.76	Unshielded	Unshielded	-
4	AC Power Cable (PC)	1.20	Unshielded	Unshielded	-
5	Parallel Cable	1.65	Shielded	Shielded	-
6	AC Adapter Cable (printer)	2.00	Unshielded	Unshielded	-
7	AC Power Cable (printer)	1.75	Unshielded	Unshielded	-

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SECTION 5: Conducted Emission

5.1 Operating environment

Test place : No. 1 semi anechoic chamber
Temperature : See data
Humidity : See data

5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane.

The rear of tabletop was located 40 cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80 cm from any other grounded conducting surface. EUT was located 80 cm from the LISN/AMN. I/O cables that were connected to the other peripherals were bundled in center. They were folded back and forth forming a bundle 30 cm to 40 cm long and were hanged at a 40 cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/AMN to the input power source. All unused 50 ohm connectors of the LISN/AMN were resistivity terminated in 50 ohm when not connected to the measuring equipment.

Photographs of the set up are shown in Appendix 3.

Frequency range : 0.15 MHz - 30 MHz
EUT position : Table top
EUT operation mode : See Clause 4.1

5.3 Test procedure

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT within a semi anechoic chamber. The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains network (AMN). An overview sweep with peak detection has been performed. The measurements have been performed with a quasi-peak detector and if required, with an average detector.

The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type : Quasi-Peak and CISPR AV
IF Bandwidth : 9 kHz

5.4 Test result

Summary of the test results: Pass

Date: September 11, 2015 Test engineer: Shinichi Miyazono

SECTION 6: Radiated Emission

6.1 Operating environment

Test place : No. 1 semi anechoic chamber
Temperature : See data
Humidity : See data

6.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0 m by 1.5 m, raised 0.8 m above the conducting ground plane.

The EUT was set on the edge of the tabletop.

Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.

Photographs of the set up are shown in Appendix 3.

6.3 Test conditions

Frequency range : 30 MHz - 300 MHz (Biconical antenna) / 300 MHz - 1000 MHz (Logperiodic antenna)
1000 MHz - 6000 MHz (Horn antenna)
Test distance : 3 m
EUT position : Table top
EUT operation mode : See Clause 4.1

6.4 Test procedure

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver.

The radiated emission measurements were made with the following detector function of the Test Receiver.

Frequency	Below 1GHz	Above 1GHz
Instrument used	Test Receiver	Test Receiver
IF Bandwidth	QP: BW 120kHz	PK: BW 1MHz, CISPR AV: BW 1MHz

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

6.5 Test result

Summary of the test results: Pass

Date: September 10 and 11, 2015

Test engineer: Shinichi Miyazono

APPENDIX 1: Data of EMI test

Conducted Emission

DATA OF CONDUCTED EMISSION TEST

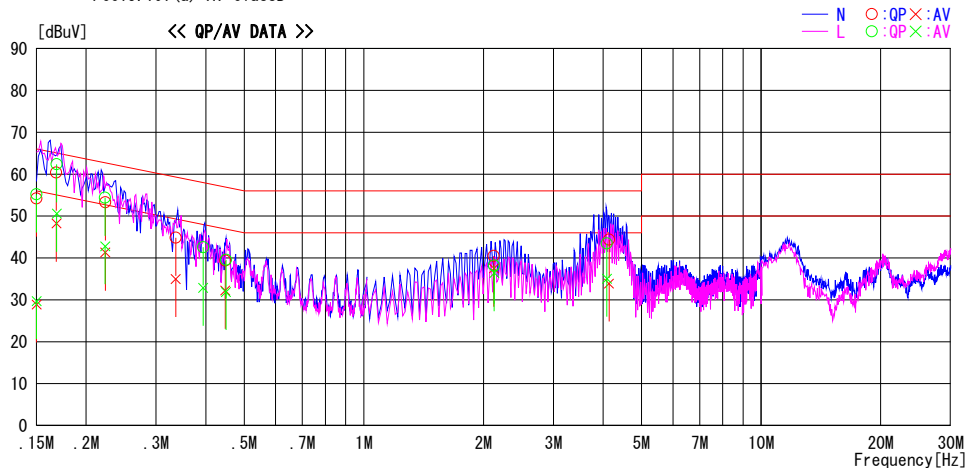
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2015/09/11

Report No. : 10946205H

Temp./Humi. : 20deg. C / 67% RH
Engineer : Shinichi Miyazono

Mode / Remarks : USB Data Com Mode

LIMIT : FCC15.107(a) QP ClassB
FCC15.107(a) AV ClassB



Frequency [MHz]	Reading Level		Corr. Factor [dB]	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15000	42.0	16.5	13.2	55.2	29.7	66.0	56.0	10.8	26.3	L	
0.15000	41.0	15.7	13.2	54.2	28.9	66.0	56.0	11.8	27.1	N	
0.16836	47.2	35.0	13.2	60.4	48.2	65.0	55.0	4.6	6.8	N	
0.16862	49.2	37.4	13.2	62.4	50.6	65.0	55.0	2.6	4.4	L	
0.22332	41.1	29.5	13.3	54.4	42.8	62.7	52.7	8.3	9.9	L	
0.22345	40.0	28.0	13.3	53.3	41.3	62.7	52.7	9.4	11.4	N	
0.33600	31.5	21.7	13.3	44.8	35.0	59.3	49.3	14.5	14.3	N	
0.39380	29.3	19.6	13.3	42.6	32.9	58.0	48.0	15.4	15.1	L	
0.44760	26.1	18.9	13.3	39.4	32.2	56.9	46.9	17.5	14.7	N	
0.44970	26.3	18.6	13.3	39.6	31.9	56.9	46.9	17.3	15.0	L	
2.12530	26.8	23.8	13.7	40.5	37.5	56.0	46.0	15.5	8.5	N	
2.12930	24.5	22.7	13.7	38.2	36.4	56.0	46.0	17.8	9.6	L	
4.09060	29.5	21.1	14.0	43.5	35.1	56.0	46.0	12.5	10.9	L	
4.14020	30.4	19.9	14.0	44.4	33.9	56.0	46.0	11.6	12.1	N	

CHART : WITH FACTOR, Peak hold data. CALCULATION : RESULT = READING + C.F (LISN + ATTEN. + CABLE)
Except for the above table : adequate margin data below the limits.

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

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Conducted Emission

DATA OF CONDUCTED EMISSION TEST

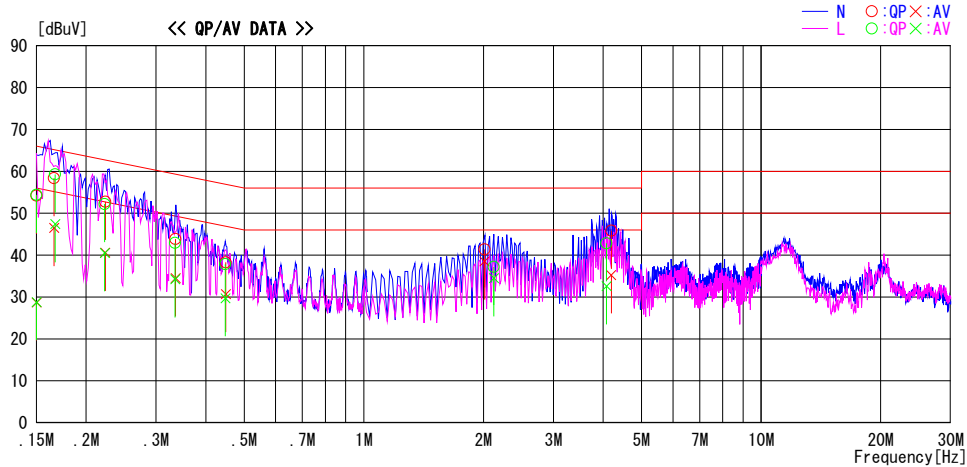
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2015/09/11

Report No. : 10946205H

Temp./Humi. : 20deg. C / 67% RH
Engineer : Shinichi Miyazono

Mode / Remarks : Standby mode

LIMIT : FCC15.107(a) QP ClassB
FCC15.107(a) AV ClassB



Frequency [MHz]	Reading Level		Corr. Factor	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15000	41.2	15.6	13.2	54.4	28.8	66.0	56.0	11.6	27.2	L	
0.15000	41.0	15.5	13.2	54.2	28.7	66.0	56.0	11.8	27.3	N	
0.16616	45.2	33.3	13.2	58.4	46.5	65.2	55.2	6.8	8.7	N	
0.16712	46.1	34.2	13.2	59.3	47.4	65.1	55.1	5.8	7.7	L	
0.22271	38.9	27.2	13.3	52.2	40.5	62.7	52.7	10.5	12.2	L	
0.22346	39.4	27.3	13.3	52.7	40.6	62.7	52.7	10.0	12.1	N	
0.33483	29.6	20.9	13.3	42.9	34.2	59.3	49.3	16.4	15.1	L	
0.33576	30.5	21.2	13.3	43.8	34.5	59.3	49.3	15.5	14.8	N	
0.44910	25.0	17.4	13.3	38.3	30.7	56.9	46.9	18.6	16.2	N	
0.44844	24.5	16.4	13.3	37.8	29.7	56.9	46.9	19.1	17.2	L	
2.12450	23.5	20.8	13.7	37.2	34.5	56.0	46.0	18.8	11.5	L	
2.01300	27.8	24.9	13.6	41.4	38.5	56.0	46.0	14.6	7.5	N	
4.08220	28.8	18.6	14.0	42.8	32.6	56.0	46.0	13.2	13.4	L	
4.19720	31.8	21.2	14.0	45.8	35.2	56.0	46.0	10.2	10.8	N	

CHART : WITH FACTOR, Peak hold data. CALCULATION : RESULT = READING + C.F (LISN + ATTEN. + CABLE)
Except for the above table : adequate margin data below the limits.

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Below 1GHz)

DATA OF RADIATED EMISSION TEST

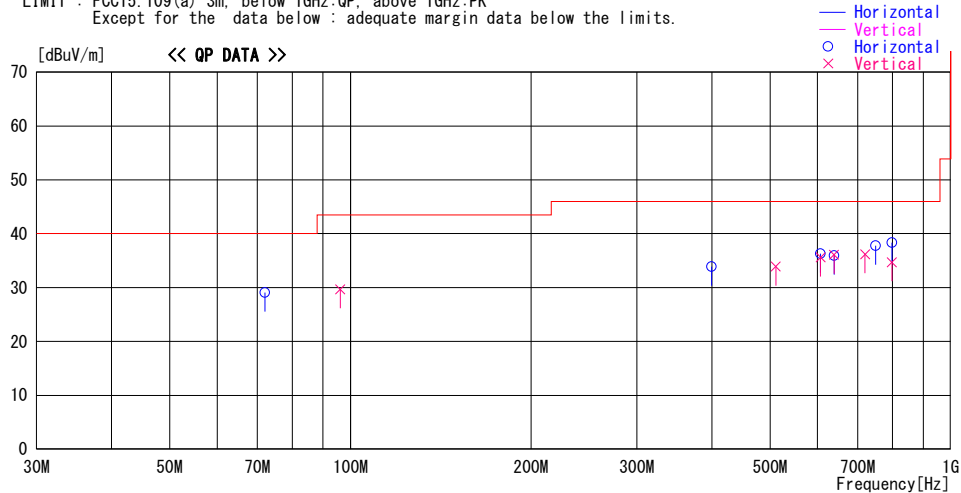
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2015/09/10

Report No. : 10946205H

Temp./Humi. : 22deg. C / 73% RH
Engineer : Shinichi Miyazono

Mode / Remarks : USB Data Com Mode Worst-Axis(Hori:X / Vert:X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
72.025	53.6	QP	6.3	-30.8	29.1	119	256	Hori.	40.0	10.9	
96.134	50.7	QP	9.4	-30.4	29.7	141	100	Vert.	43.5	13.8	
399.826	43.8	QP	17.5	-27.4	33.9	331	100	Hori.	46.0	12.1	
511.266	41.8	QP	18.2	-26.1	33.9	352	100	Vert.	46.0	12.1	
607.129	42.4	QP	19.5	-25.6	36.3	158	135	Hori.	46.0	9.7	
607.130	41.7	QP	19.5	-25.6	35.6	0	100	Vert.	46.0	10.4	
639.085	41.4	QP	19.9	-25.4	35.9	151	118	Hori.	46.0	10.1	
639.088	41.6	QP	19.9	-25.4	36.1	0	100	Vert.	46.0	9.9	
719.987	40.5	QP	20.7	-25.0	36.2	78	100	Vert.	46.0	9.8	
749.994	41.5	QP	21.1	-24.8	37.8	77	118	Hori.	46.0	8.2	
798.020	41.1	QP	21.7	-24.5	38.3	161	113	Hori.	46.0	7.7	
798.080	37.5	QP	21.7	-24.5	34.7	21	100	Vert.	46.0	11.3	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE + ATTEN. - GAIN(AMP))

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Below 1GHz)

DATA OF RADIATED EMISSION TEST

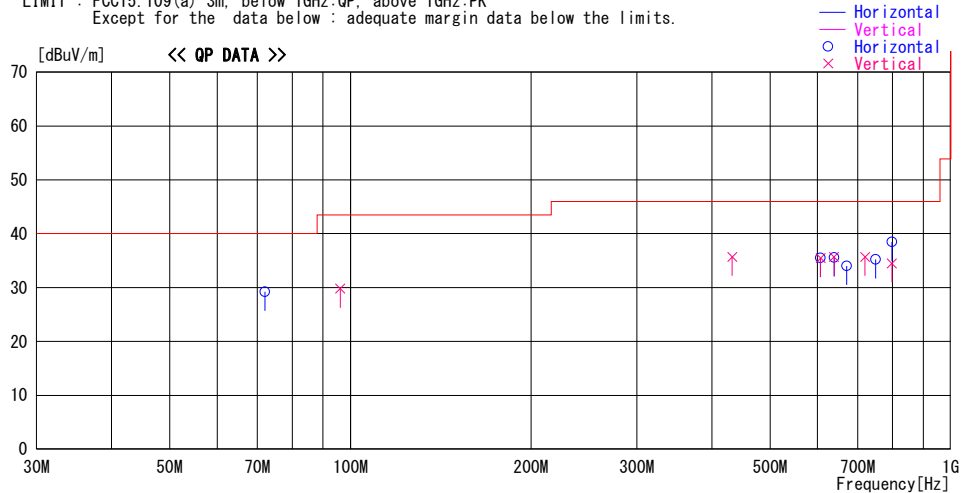
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2015/09/10

Report No. : 10946205H

Temp./Humi. : 22deg. C / 73% RH
Engineer : Shinichi Miyazono

Mode / Remarks : Standby mode Worst-Axis(Hori:X / Vert:X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
72.023	53.7	QP	6.3	-30.8	29.2	129	244	Hori.	40.0	10.8	
96.133	50.8	QP	9.4	-30.4	29.8	155	100	Vert.	43.5	13.7	
432.606	45.1	QP	17.7	-27.1	35.7	176	100	Vert.	46.0	10.3	
607.129	41.6	QP	19.5	-25.6	35.5	0	100	Vert.	46.0	10.5	
607.131	41.6	QP	19.5	-25.6	35.5	161	128	Hori.	46.0	10.5	
639.084	41.1	QP	19.9	-25.4	35.6	156	115	Hori.	46.0	10.4	
639.084	41.2	QP	19.9	-25.4	35.7	2	100	Vert.	46.0	10.3	
671.038	39.1	QP	20.2	-25.3	34.0	150	107	Hori.	46.0	12.0	
719.983	40.0	QP	20.7	-25.0	35.7	90	100	Vert.	46.0	10.3	
749.989	38.9	QP	21.1	-24.8	35.2	83	125	Hori.	46.0	10.8	
797.920	41.3	QP	21.7	-24.5	38.5	157	100	Hori.	46.0	7.5	
798.000	37.3	QP	21.7	-24.5	34.5	27	100	Vert.	46.0	11.5	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE + ATTEN. - GAIN(AMP))

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Above 1GHz)

DATA OF RADIATED EMISSION TEST

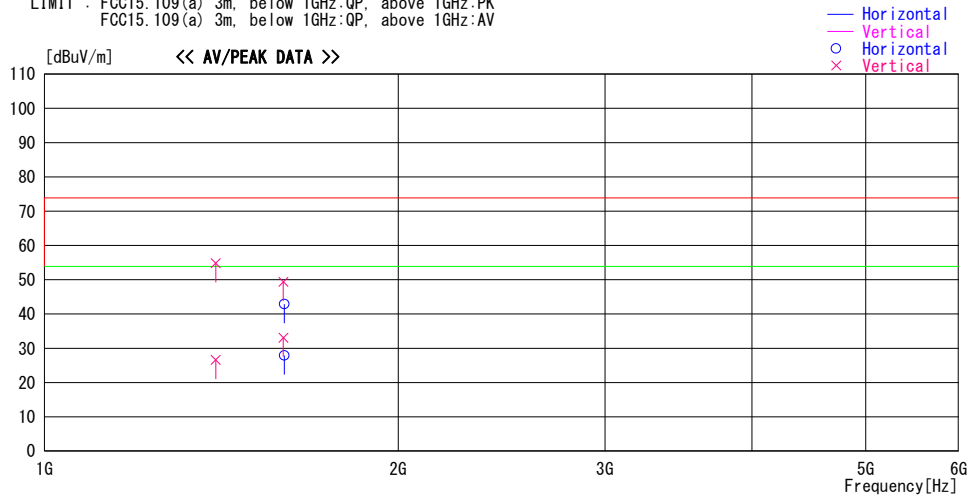
UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2015/09/11

Report No. : 10946205H

Temp./Humi. : 20deg. C / 67% RH
Engineer : Shinichi Miyazono

Mode / Remarks : USB Data Com Mode Worst-Axis(Hori: / Vert: X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
1398.800	64.1	PK	25.0	-34.3	54.8	350	325	Vert.	73.9	19.1	
1398.800	35.9	AV	25.0	-34.3	26.6	350	325	Vert.	53.9	27.3	
1596.520	57.8	PK	25.6	-34.0	49.4	359	270	Vert.	73.9	24.5	
1596.520	41.5	AV	25.6	-34.0	33.1	359	270	Vert.	53.9	20.8	
1599.999	51.3	PK	25.6	-34.0	42.9	335	100	Hori.	73.9	31.0	
1599.999	36.3	AV	25.6	-34.0	27.9	335	100	Hori.	53.9	26.0	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE - GAIN(AMP))

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission (Above 1GHz)

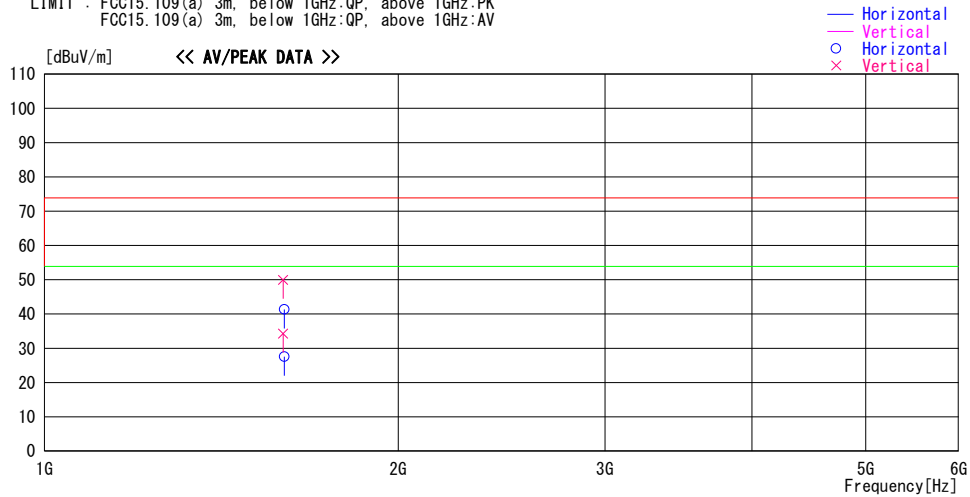
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Ise EMC Lab. No.1 Semi Anechoic Chamber
Date : 2015/09/11

Report No. : 10946205H
Temp./Humi. : 20deg. C / 67% RH
Engineer : Shinichi Miyazono

Mode / Remarks : Standby mode Worst-Axis(Hori: / Vert: X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
1596.120	58.4	PK	25.6	-34.0	50.0	350	347	Vert.	73.9	23.9	
1596.120	42.7	AV	25.6	-34.0	34.3	350	347	Vert.	53.9	19.6	
1599.993	49.8	PK	25.6	-34.0	41.4	136	378	Hori.	73.9	32.5	
1599.993	36.0	AV	25.6	-34.0	27.6	136	378	Hori.	53.9	26.3	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION : RESULT = READING + ANT FACTOR + LOSS & GAIN(CABLE - GAIN(AMP))

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

APPENDIX 2: Test instruments

EMI Test Instruments

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-01	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 10m	DA-06881	RE/CE	2014/09/01 * 12
MOS-27	Thermo-Hygrometer	CUSTOM	CTH-201	A08Q26	RE/CE	2015/01/13 * 12
MJM-21	Measure	KOMELON	KMC-36	-	RE/CE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE/CE	-
MTR-09	EMI Test Receiver	Rohde & Schwarz	ESU26	100412	RE/CE	2015/06/08 * 12
KBA-05	Biconical Antenna	Schwarzbeck	BBA9106	2513	RE	2014/11/22 * 12
KLA-04	Logperiodic Antenna	Schwarzbeck	USLP9143	361	RE	2014/11/22 * 12
MAT-08	Attenuator(6dB)	Weinschel Corp	2	BK7971	RE	2014/11/20 * 12
MCC-02	Coaxial Cable	Suhner/storm/Agilent/TSJ	-	-	RE	2014/09/12 * 12
MPA-19	Pre Amplifier	MITEQ	MLA-10K01-B01-35	1237616	RE	2015/02/03 * 12
MMM-03	Digital Tester	Fluke	FLUKE 26-3	78030621	RE	2015/08/19 * 12
MLS-24	LISN(AMN)	Schwarzbeck	NSLK8127	8127-730	CE(EUT)	2015/07/10 * 12
MLS-26	LISN(AMN)	Schwarzbeck	NSLK8127	8127-732	CE(AE)	2015/07/17 * 12
MTA-30	Terminator	TME	CT-01	-	CE	2015/01/19 * 12
MCC-03	Coaxial Cable	Fujikura/Suhner/TSJ	5D-2W(20m)/3D-2W(7.5m)/RG400u(1.5m)/RFM-E421(Switcher)	- /01068(Switcher)	CE	2014/09/12 * 12
MAT-64	Attenuator(13dB)	JFW Industries, Inc.	50FP-013H2 N	-	CE	2015/01/29 * 12
MHA-05	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	253	RE	2015/05/18 * 12
MPA-01	Pre Amplifier	Agilent	8449B	3008A01671	RE	2015/02/04 * 12
MCC-141	Microwave Cable	Junkosha	MWX221	1305S002R(1m) / 1405S146(5m)	RE	2015/06/22 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

CE: Conducted Emissions

RE: Radiated Emissions

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